

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination TOMIYASU ET AL.	
		Examiner Holly Rickman	Art Unit 1773	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lee et al. , "Effects of Cr Intermediate Layers on coCrPt Thin film Media on NiAl Underlayers", IEEE Trans Magn., Vol. 31, No. 6, Nov. 1995, pp 2728-2730
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